Advanced
LINEAR
Devices, Inc.

## QUAD/DUAL N-CHANNEL ZERO THRESHOLD ${ }^{\text {TM }}$ EPAD $^{\circledR}$ MATCHED PAIR MOSFET ARRAY

## GENERAL DESCRIPTION

ALD110800A/ALD110800/ALD110900A/ALD110900 are monolithic quad/dual N-Channel MOSFETs matched at the factory using ALD's proven EPAD ${ }^{\circledR}$ CMOS technology. These devices are intended for low voltage, small signal applications. The ALD110800/ALD110900 features zero threshold voltage, which reduces or eliminates input to output voltage level shift, including circuits where the signal is referenced to GND or $\mathrm{V}+$. This feature greatly reduces output signal voltage level shift and enhances signal operating range, especially for very low operating voltage environments. With these zero threshold devices an analog circuit with multiple stages can be constructed to operate at extremely low supply or bias voltage levels. As an example, an input amplifier stage operating at 0.2 V supply voltage has been demonstrated.

ALD110800A/ALD110800/ALD110900A/ALD110900 matched pair MOSFETs are designed for exceptional device electrical characteristics matching. As these devices are on the same monolithic chip, they also exhibit excellent tempco tracking characteristics. They are versatile as design components for a broad range of analog applications such as basic building blocks for current sources, differential amplifier input stages, transmission gates, and multiplexer applications.

Besides matched pair electrical characteristics, each individual MOSFET also exhibits well controlled parameters, enabling the user to depend on tight design limits. Even units from different batches and different date of manufacture have correspondingly well matched characteristics.

These devices are built for minimum offset voltage and differential thermal response, and they are designed for switching and amplifying applications in +0.2 V to +10 V systems where low input bias current, low input capacitance and fast switching speed are desired. The $\mathrm{V}_{\mathrm{GS}}(\mathrm{th})$ of these devices are set at +0.0 V , which classify them as both enhancement mode and depletion mode devices. When the gate is set at 0.0 V , the drain current $=+1 \mu \mathrm{~A} @ \mathrm{~V}_{\mathrm{DS}}=1+0.1 \mathrm{~V}$, which allow a class of circuits with output voltage level biased at or near input voltage level without voltage level shift. These devices exhibit same well controlled turn-off and sub-threshold characteristics as standard enhancement mode MOSFETs.

The ALD110800A/ALD110800/ALD110900A/ALD110900 are MOSFET devices that feature high input impedance $\left(10^{12} \Omega\right)$ and high DC current gain $\left(>10^{8}\right)$. A sample calculation of the DC current gain at a drain current of 3 mA and input leakage current of 30 pA at $25^{\circ} \mathrm{C}$ is $=3 \mathrm{~mA} /$ $30 p A=100,000,000$. For most applications, connect $V+$ pin to the most positive voltage potential (or left open unused) and $V$ - and $N / C$ pins to the most negative voltage potential in the system. All other pins must have voltages within these voltage limits.

## ORDERING INFORMATION

| Operating Temperature Range*$0^{\circ} \mathrm{C} \text { to }+70^{\circ} \mathrm{C} \quad 0^{\circ} \mathrm{C} \text { to }+70^{\circ} \mathrm{C}$ |  |  |  |
| :---: | :---: | :---: | :---: |
|  |  |  |  |
| 16-Pin | 16-Pin | 8-Pin | 8-Pin |
| Plastic Dip | SOIC | Plastic Dip | SOIC |
| Package | Package | Package | Package |
| ALD110800APC | ALD110800ASC | ALD110900APA | ALD110900ASA |
| ALD110800PC | ALD110800SC | ALD110900PA | ALD110900SA |

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## FEATURES

- Precision zero threshold voltage mode
- Nominal RDS(ON) @VGS=0.0V of $104 \mathrm{~K} \Omega$
- Matched MOSFET to MOSFET characteristics
- Tight lot to lot parametric control
- $\mathrm{VGS}(\mathrm{th})$ match (VOS) to 2 mV and 10 mV
- Positive, zero, and negative $\mathrm{V}_{\mathrm{GS}}(\mathrm{th})$ tempco
- Low input capacitance
- Low input/output leakage currents


## APPLICATIONS

- Very low voltage analog and digital circuits
- Zero power fail safe circuits
- Backup battery circuits \& power failure detector
- Low level voltage clamp \& zero crossing detector
- Source followers and buffers
- Precision current mirrors and current sources
- Capacitives probes and sensor interfaces
- Charge detectors and charge integrators
- Differential amplifier input stage
- High side switches
- Peak detectors and level shifters
- Sample and Hold
- Current multipliers
- Analog switches / multiplexers
- Voltage comparators and level shifters


## PIN CONFIGURATION



## ABSOLUTE MAXIMUM RATINGS

Drain-Source voltage, $V_{D S}$
10.6 V

Gate-Source voltage, $\mathrm{V}_{\mathrm{GS}}$ $\qquad$ . 0.6

Power dissipation $\qquad$
$\qquad$ 10.6 V

Operating temperature range PA, SA, PC, SC package $\qquad$ $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$
Storage temperature range $\qquad$ $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Lead temperature, 10 seconds $\qquad$ $+260^{\circ} \mathrm{C}$

## OPERATING ELECTRICAL CHARACTERISTICS

## V+ = +5V (or open) V- = GND TA = $25^{\circ} \mathrm{C}$ unless otherwise specified

CAUTION: ESD Sensitive Device. Use static control procedures in ESD controlled environment.

| Parameter | Symbol | ALD110800A / ALD110900A |  |  | ALD110800/ ALD110900 |  |  | Unit | Test Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max | Min | Typ | Max |  |  |
| Gate Threshold Voltage | VGS(th) | -0.01 | 0.00 | 0.01 | -0.02 | 0.00 | 0.02 | V | $\mathrm{IDS}=1 \mu \mathrm{~A}, \mathrm{~V} D S=0.1 \mathrm{~V}$ |
| Offset Voltage $\mathrm{V}_{\mathrm{GS}}(\mathrm{th}) 1$ - $\mathrm{V}_{\mathrm{GS}}(\mathrm{th}) 2$ | VOS |  | 1 | 2 |  | 2 | 10 | mV |  |
| Offset Voltage Tempco | TCVOS |  | 5 |  |  | 5 |  | $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}$ | $\mathrm{V}_{\mathrm{DS} 1}=\mathrm{V}_{\text {DS2 }}$ |
| GateThreshold Voltage Tempco | TCVGS(th) |  | $\begin{array}{r} -1.7 \\ 0.0 \\ +1.6 \end{array}$ |  |  | -1.7 0.0 +1.6 |  | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ | $\begin{aligned} & \mathrm{ID}=1 \mu \mathrm{~A}, \mathrm{~V} D=0.1 \mathrm{~V} \\ & \mathrm{ID}=20 \mu \mathrm{~A}, \mathrm{~V} D=0.1 \mathrm{~V} \\ & \mathrm{ID}=40 \mu \mathrm{~A}, \mathrm{~V} D=0.1 \mathrm{~V} \\ & \hline \end{aligned}$ |
| On Drain Current | IDS (ON) |  | $\begin{array}{r} 12.0 \\ 3.0 \end{array}$ |  |  | $\begin{array}{r} 12.0 \\ 3.0 \end{array}$ |  | mA | $\begin{aligned} & \mathrm{V}_{\mathrm{GS}}=+9.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=+5 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{GS}}=+4.0 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=+5 \mathrm{~V} \end{aligned}$ |
| Forward Transconductance | GFS |  | 1.4 |  |  | 1.4 |  | mmho | $\begin{aligned} & \text { VGS }=+4.0 \mathrm{~V} \\ & \text { VDS }=+9.0 \mathrm{~V} \end{aligned}$ |
| Transconductance Mismatch | $\Delta$ GFS |  | 1.8 |  |  | 1.8 |  | \% |  |
| Output Conductance | GOS |  | 68 |  |  | 68 |  | $\mu \mathrm{mho}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{GS}}=+4.0 \mathrm{~V} \\ & \mathrm{VDS}=+9.0 \mathrm{~V} \end{aligned}$ |
| Drain Source On Resistance | RDS (ON) |  | 500 |  |  | 500 |  | $\Omega$ | $\begin{aligned} & \mathrm{VDS}=+0.1 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{GS}}=+4.0 \mathrm{~V} \end{aligned}$ |
| Drain Source On Resistance | RDS (ON) |  | 104 |  |  | 104 |  | K $\Omega$ | $\begin{aligned} & \mathrm{VDS}=+0.1 \mathrm{~V} \\ & \mathrm{VGS}=+0.0 \mathrm{~V} \end{aligned}$ |
| Drain Source On Resistance Tolerance | $\Delta \mathrm{RDS}$ (ON) |  | 5 |  |  | 5 |  | \% | $\begin{aligned} & \mathrm{VDS}=+0.1 \mathrm{~V} \\ & \mathrm{VGS}=+4.0 \mathrm{~V} \end{aligned}$ |
| Drain Source On Resistance Mismatch | $\Delta \mathrm{RDS}$ (ON) |  | 0.5 |  |  | 0.5 |  | \% |  |
| Drain Source Breakdown Voltage | BVDSX | 10 |  |  | 10 |  |  | V | $\begin{aligned} & \mathrm{IDS}=1.0 \mu \mathrm{~A} \\ & \mathrm{~V}^{-}=\mathrm{V}_{\mathrm{GS}}=-1.0 \mathrm{~V} \end{aligned}$ |
| Drain Source Leakage Current ${ }^{1}$ | IDS (OFF) |  | 10 | $\begin{array}{r} 400 \\ 4 \end{array}$ |  | 10 | $\begin{array}{r} 400 \\ 4 \end{array}$ | pA <br> nA | $\begin{aligned} & \mathrm{VGS}=-1.0 \mathrm{~V}, \mathrm{~V} D \mathrm{DS}=+5 \mathrm{~V} \\ & \mathrm{~V}^{-}=-5 \mathrm{~V} \\ & \mathrm{~T}_{\mathrm{A}}=125^{\circ} \mathrm{C} \\ & \hline \end{aligned}$ |
| Gate Leakage Current ${ }^{1}$ | IGSS |  | 5 | 30 1 |  | 5 | $\begin{array}{r} 30 \\ 1 \end{array}$ | $\begin{aligned} & \mathrm{pA} \\ & \mathrm{nA} \end{aligned}$ | $\begin{aligned} & V_{D S}=0 V V_{G S}=+10 \mathrm{~V} \\ & T_{A}=125^{\circ} \mathrm{C} \end{aligned}$ |
| Input Capacitance | CISS |  | 2.5 |  |  | 2.5 |  | pF |  |
| Transfer Reverse Capacitance | CRSS |  | 0.1 |  |  | 0.1 |  | pF |  |
| Turn-on Delay Time | ton |  | 10 |  |  | 10 |  | ns | $\mathrm{V}+=5 \mathrm{~V} \quad \mathrm{R}_{\mathrm{L}}=5 \mathrm{~K} \Omega$ |
| Turn-off Delay Time | toff |  | 10 |  |  | 10 |  | ns | $\mathrm{V}+=5 \mathrm{~V} \quad \mathrm{RL}=5 \mathrm{~K} \Omega$ |
| Crosstalk |  |  | 60 |  |  | 60 |  | dB | $\mathrm{f}=100 \mathrm{KHz}$ |

Notes: ${ }^{1}$ Consists of junction leakage currents


[^0]:    * Contact factory for industrial temp. range or user-specified threshold voltage values

